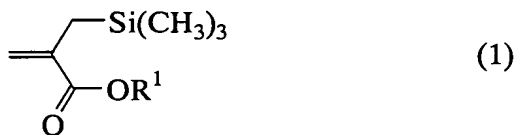


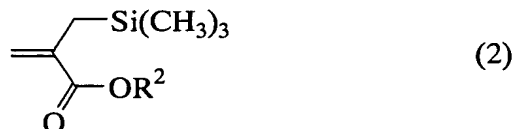
CLAIMS:

1. A polymerizable silicon-containing compound having the general formula (1):



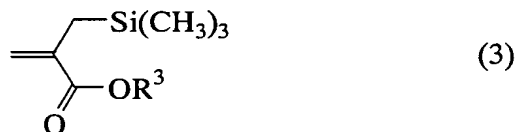
wherein R¹ is a hydrogen atom, halogen atom or monovalent organic group.

2. A polymerizable silicon-containing ester derivative having an acid eliminatable substituent group according to claim 1, having the general formula (2):



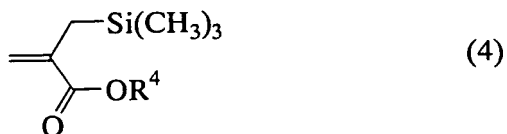
wherein R² is an acid labile group.

3. A polymerizable silicon-containing ester derivative having a polar group according to claim 1, having the general formula (3):



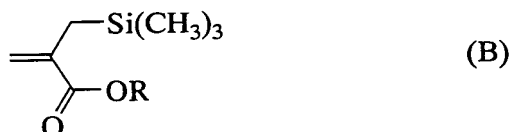
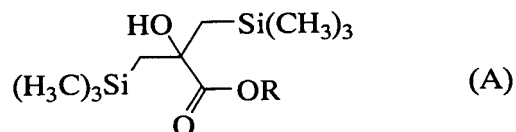
20 wherein R³ is a monovalent organic group of 2 to 30 carbon atoms containing an oxygen functional group such as hydroxyl, carbonyl, ether bond or ester bond.

4. A polymerizable silicon-containing ester derivative having a silicon-containing group according to claim 1, having the general formula (4):



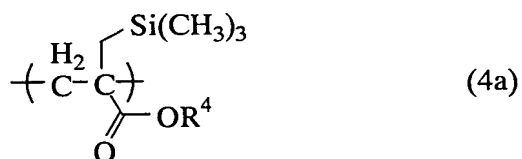
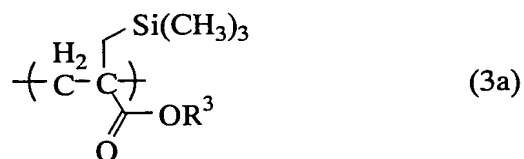
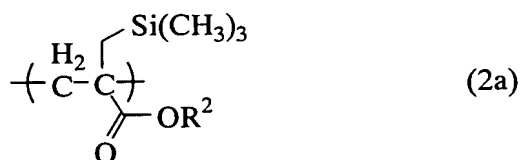
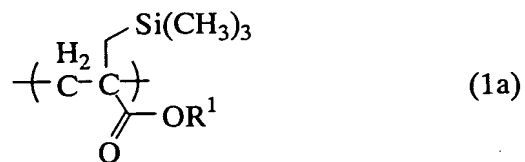
5 wherein R⁴ is a monovalent organic group of 3 to 30 carbon atoms containing at least one silicon atom.

5. A method for preparing a polymerizable silicon-containing compound having the general formula (B), comprising the steps of reacting an oxalate with a trimethylsilylmethyl-metal compound to form a β-hydroxysilyl compound having the general formula (A) and subjecting the β-hydroxysilyl compound to Peterson elimination reaction,



15 wherein R stands for R¹, R², R³ or R⁴, R¹ is a hydrogen atom, halogen atom or monovalent organic group, R² is an acid labile group, R³ is a monovalent organic group of 2 to 30 carbon atoms containing an oxygen functional group, and R⁴ is a monovalent organic group of 3 to 30 carbon atoms containing
20 at least one silicon atom.

6. A polymer comprising recurring units of the general formula (1a), (2a), (3a) or (4a) and having a weight average molecular weight of 2,000 to 100,000,



5 wherein R¹ is a hydrogen atom, halogen atom or monovalent organic group, R² is an acid labile group, R³ is a monovalent organic group of 2 to 30 carbon atoms containing an oxygen functional group, and R⁴ is a monovalent organic group of 3 to 30 carbon atoms containing at least one silicon atom.

7. The polymer of claim 6 further comprising recurring units of at least one type having the general formula (5a) or (6a):



5 wherein Y¹, Y², Y³ and Y⁴ are each independently selected from the group consisting of hydrogen, alkyl groups, aryl groups, halogen atoms, alkoxycarbonyl groups, alkoxycarbonylmethyl groups, cyano groups, fluorinated alkyl groups, and silicon
10 atom-containing monovalent organic groups of 3 to 30 carbon atoms, any two of Y¹, Y², Y³ and Y⁴ may bond together to form a ring, Z is an oxygen atom or NR⁵, and R⁵ is hydrogen, hydroxyl or alkyl.

8. A resist composition comprising the polymer of claim 6.

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9. A chemically amplified positive resist composition comprising

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- (A) the polymer of claim 6,
- (B) a photoacid generator, and
- (C) an organic solvent.

10. A method for forming a pattern, comprising the steps of:

25 applying the positive resist composition of claim 9 onto an organic film on a substrate to form a coating, prebaking the coating to form a resist film, exposing a circuitry pattern region of the resist film to radiation, post-exposure baking the resist film,

developing the resist film with an aqueous alkaline solution to dissolve away the exposed area, thereby forming a resist pattern, and

processing the organic film with an oxygen plasma
5 generated by a dry etching apparatus.